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Test on Good Board	
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Set .svf File	
Run	
PseudoCLI Feature	

Note: There may be some changes between versions. So, your software may look a bit different from this manual.

Attention: To get better test result and wider test coverage, please keep FPGA, CPLDs blank when testing, and do not program or configure them before test. And please keep CPUs in idle status, i.e. do not program their Boot ROMs or Flashs before test.

Main User Interface



Before Start

1, Please get the BSDL file of DUT (Device Under Test) and put them in the same folder with software. If there multi devices in JTAG chain, please try to get all BSDL files. And if you could not get every BSDL file, you must know each device's JTAG instruction length.

- 2, Power off the target board.
- 3, Connect the cables between computer and target board.
- 4, Power up the target board;
- 5, Click to run the software.

6, When you see the main UI dialog, please select menu **Test** – **Scan JTAG Chain** to check how many devices detected by the software. See screenshot below:

1	🖁 Bo	ounda	ary Scan Test		x
	File	Test	Process Options Utilites	Log Help	
			Scan JTAG Chain		-
			Inter-device Test Single Device Test		
			Manual Test		
					-
	•			•	

If any device is detected, device ID and other info will be displayed. See screenshot below:



```
Another log example of Xilinx ML505 reference design board.
Cable type: 10; Target power: -1; Frequency: 6000000
Scanning JTAG chain ...
5 device(s) detected.
Getting IDCODE_REGISTERs of all devices ...
Get done.
11110101000001011001000010010011
11110101000001011001000010010011
01011001011000001000000010010011
11000010101010010110000010010011
Index Ver.
             Device
                             MFG.
                                       Comments
   0
     1111
             0101000001011001 00001001001
                                           Xilinx XCF32P
             0101000001011001 00001001001
   1 1111
                                           Xilinx XCF32P
   2
     0101
             1001011000001000 00001001001
                                           Xilinx XC95144XL
      0000
             101000000000001 00001001001
                                           Xilinx XCCACE
   3
   4
      1100
             0010101010010110 00001001001
                                           Xilinx XC5LX50T
```

If no device detected, a message box is popped, and please refer to troubleshooting

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below.	
BSTestd(ENU)	
0 device(s) detected.	
确定	

If no device detected, please check:

- Cable is connected correctly;
- JTAG circuit of target board works;
- Target board is powered OK;

If the device list doesn't match with the board, please read target board's manual to confirm jumper settings or configurations. If you are using WH-USB-HiJTAG cable, you could try to slow the TCK frequency, please refer to <u>Set TCK Frequency</u>.

Only when device list detected by the software matches with the board, you can do any test with the software.

Set TCK Frequency

Select menu Options / TCK Frequency. See screenshot below:

1	鴅 Bo	oundar	y Scan Tes	t 💷	
ſ	<u>F</u> ile	<u>T</u> est	<u>P</u> rocess	Options Utilites Log Help	
				TCK Frequency	*
	4				
					*

Input the frequency you want to set. For example, if you want to change TCK frequency to 15MHz, you should input 15000000.

See screenshots below:

TCK Frequency		×
Enter frequency to set:		
15000000		
	<u>o</u> k	Cancel

To WH-USB-HiJTAG cable, the frequency could be 30000000, 1500000, 10000000, and 6000000 and so on.

To WH-USB-JTAG cable, the frequency could be 6000000, 3000000 and so on.

Manual Test

The system can display status of JTAG chip's pins (something like an oscilloscope or logic analyzer), and can control the chip to output a user defined waveform (something like a signal generator). You can find issues in welding (open, short, etc.) or PCB production by analyzing the phenomenon. Also, it can be used as debugging tool.

Preparation

elect	meni	1 Test – Manual Tes	t. See sc	reensh	ot below:		
🖁 Bo	ounda	ary Scan Test					
<u>F</u> ile	Test	<u>Process</u> Options	<u>U</u> tilites	Log	<u>H</u> elp		
		Scan JTAG Chain					
		Inter-device Test					
		Single Device Test					
		Manual Test					
	_						

Sel

You will be asked whether you have BSDL file for every device in JTAG chain. See screenshot below:



If you have BSDL file for every device

The software will let you choose BSDL file of device one by one. See screenshot below: X Browse BSDL file of device at index 0 (based on 0) in chain... 📙 « David 🕨 My Dropbox 🕨 Software 🕨 bsdl 搜索 bsdl Q 新建文件夹 ? 组织 ▼ 🖹 Photos ٨ 修改日期 类____ 名称 💧 Public 88E1011_128pin(MV-S900005-B2).bsdl 2005/4/15 17:21 BS Software 88E1340x_88E1322x_TFBGA196.bsd 2012/4/14 22:14 BS bsdl at91sam9260_bga.bsd 2007/9/3 15:06 BS 📗 ibis at91sam9260_pqfp.bsd 2007/9/3 15:06 BS 📗 iss bcm5328_091702.bsd 2002/12/5 8:59 BS BCM5482.A1.bsd 2012/4/1 10:55 📗 lib BS bcm6421.bsd 2012/4/1 10:54 BS 🃗 pdml bcm6510a0.bsd 2012/4/14 22:21 BS Self bcm54980.bsd 2012/4/1 10:56 BS Setup bcm56624.bsdl 2007/10/1 10:36 BS 1 SWIFT BSDL Files (*.bsd;*.bsm;*.bsdl) File name: • Ŧ Open Cancel

The software will parse each device's BSDL, and compare IDCODE in BSDL with detected IDCODE. If mismatch found, a message box is popped like this:



Note: Some JTAG device doesn't implement IDCODE instruction, and no IDCODE register in BSDL. So, the software could not judge whether BSDL file and device is matched or not. It's just a reminder.

If check passed, you will come to Manual Test dialog.

If you don't get BSDL file for every device

You will see a configuration dialog:

Manual Test Configuration	×
Prefix Instruction Length Prefix Data	Length
Browse BSDL File	Index in Chain 0
Postfix Instruction Length Postfix Data	a Length
OKCancel	
	.4

Prefix Instruction Length

Please input JTAG instruction length of all other devices ahead of DUT. If there are more than one devices, please split them with '|' character. For example, '4 | 5' means there are two devices ahead of DUT in JTAG chain, and device at index 0 has a 4-bit JTAG instruction while device at index 1 has a 5-bit JTAG instruction. And you could find that the DUT is at index 2. Must left blank when no prefix device.

Post Instruction Length

Please input JTAG instruction length of all other devices behind of DUT. Refer to <u>Prefix</u> <u>Instruction Length</u>. Must left blank when no postfix device.

Setting

	Manual Test			
<u> </u>	e <u>T</u> est <u>A</u> dva	nced		
<u>D</u> ev	ice Lists (Double C	Click to Set)		
I.	BSDL file			Operation
0	E: Wy Document	ts\David\My Dropt	oox\Software\bsdl\EP2C8Q208.BSD	Bypass
Inp	uts			
I.	Name	Formatted V	Value	

By default the software will set operation to **Bypass**.

• Double click DUT in **Device Lists** to edit settings. You will see **Setting for Device n** dialog (n means index in JTAG chain and index begins with 0).

🔳 Setti	ng for Device 0				×	
<u>File T</u>	ools <u>O</u> ption					
Operation	Bypass		-			
Output Se	etting					
BSC No.	0 Vutp	ut		Add	Update Delete	
Cell	Name	Location	O Value			
Input Set	tting					
Name	BSC	Numbers		Add	Update Delete	
Name	Cell Elements					
ок	Cancel					

Operation

Change **Operation** to **Test** (for those devices that will not be tested, please keep '**Bypass**').

I/O

Utility for Setting I/O

Select menu Utilities / Edit I/O Settings in Table.... See screenshot below:

Setti	ng for Device 0
File T	ools Option
<u>O</u> pera	Lookup Cell by Pin Location
Outpu	Lookup Cell by Port Name
BSC N	Add Cells Automatically with Regular Expression
Cell	Edit I/O Settings in Table
Input Set	tting
Name	BSC Numbers Add Update Delete
Name	Cell Elements
OK	Cancel

You will see I/O Setting dialog popped:

	I/O Setting						×
1	Cell Number	Port Name	Pin Location	Cell Function	Output Setting	Watch Input	<u>^</u>
	0	IO208	208	INPUT			
	1	*		ONTROL			
	2	IO208	208	OUTPUT3	z - Disabled 💻		
	3	IO207	207	INPUT			
	4	*		ONTROL			
!	5	IO207	207	OUTPUT3	z - Disabled 💻		
1	6	IO206	206	INPUT			
	7	*		ONTROL			
	8	IO206	206	OUTPUT3	z - Disabled 💻		
9	9	IO205	205	INPUT			
	10	*		ONTROL			-
-0	OK _	Cancel					

If you want to control a pin to output, please type the output pattern string in Edit box of the cell, or please choose output value from Combobxo of the cell.

If you want to observe input value of a pin, please tick the checkbox.

When finished, please click **OK** to return **to Setting for Device n** dialog.

Utilities

Lookup BSC No. by Pin Location

Select menu Utilities –Lookup cell by pin location...:

🔳 Se	tting	for Device 0	×			
<u>F</u> ile	<u>T</u> oo	ls <u>O</u> ption				
Opera	Opera Lookup Cell by Pin Location					
Outpu		Lookup Cell by Port Name				
BSC N		Add Cells Automatically with Regular Expression	Delete			
Cell		Edit I/O Settings in Table				
Input 9	Settin	g				
Name	Name BSC Numbers Add Update Delete					
Name	Name Cell Elements					
_	ОК	Cancel				

Input pin location. See screenshot below:

Pin Location	— X
Enter pin location:	
2	
	OK Cancel

Click OK button.

The software will lookup BSDL file for the cell, and display search result.

2 Input: NOTFOUND : Output: 593 OK Cancel	Result	×
Input: NOTFOUND ; Output: 593	2	
OK Cancel	Input: NOTFOUND ; Output: 593	
	ŪK	Cancel

Now, you could copy corresponding cell number to **BSC No.** field for input or output setting.

Lookup BSC No. by Port Name

Similarly, you could lookup a cell by port name.

Select menu Utilities –Lookup cell by port name....

Set	ting for Device 0	x					
<u>F</u> ile	Tools Option						
<u>O</u> pera	Lookup Cell by Pin Location						
Outpu	Lookup Cell by Port Name						
BSC N	Add Cells Automatically with Regular Expression	Delete					
Cell	Edit I/O Settings in Table						
Input S	Input Setting						
Name	BSC Numbers Add Update	Delete					
Name	Cell Elements						
	OK Cancel						

Output Setting

Input one in edit box behind **BSC No.** then input value ('0' or '1') in edit box after **Output**.

Note: In fact, the software could output any pattern. That's to say, you could input a binary string in the Output edit box. For example, if you set Output to 01, the software will output a 1:1 square waveform. If the Output pattern is 1000, the duty-cycle of output waveform will be 1:3.

Do above steps repeatedly until you have set all outputs.

Input Setting

Input a name in edit box after 'Name', and input a cell number in edit box after **BSC number**, and click **Add** button.

Note: You can watch many input pins together and combine them in a group. Just input multi cell numbers and split them with ','.

Do above steps repeatedly until you have set all inputs.

Here	is	an	exam	ple:
				P

💽 Setti	ng for Device 0						
<u>File T</u> o	<u>File Tools Option</u>						
Operation	Operation Test						
Output Se	etting						
BSC No.	0 Vutp	ut		Add Update Delete			
Cell	Name	Location	0	Value 🔶			
584	IO5	5	Y	11111111111111111111111111111111110.			
578	IO8	8	Y	000000000000000000000000000000000000000			
•			111	4			
Input Set	ting						
Name	BSC	Numbers		Add Update Delete			
Name	Cell Elements						
dk7	225						
ОК	Cancel						

More Devices...

- Click **OK** button to return to **Manual Test** dialog.
- Do above steps repeatedly until you have set all devices.

Test

Test submenus:

🔳 Manua	l Test		- • ×
File Tes	t Advanced		
Device	Single Read	1	
I. I	Single Write		Operation
0	Single RW	ox\Software\bsdl\EP2C8Q208.BSD	Test
	Cont. Read		
	Cont. Write		
Inputs	Cont. RW		
I. N	Stop	Value	
0 clk7			
-			

Single Read: The software will read input value to pins one time of every device whose operation is in **Test**.

Single Write: The software will drive output value to pins one time of every device whose operation is in **Test**.

Single RW: Single Write and Single Read.

Cont. Read: The software will loop doing Single Read until menu Test – Stop is clicked.

Cont. Write: The software will loop doing Single Write until menu Test – Stop is clicked.

Cont. RW: The software will loop doing Single RW until menu Test – Stop is clicked.

Inter-Device Test

The system reads schematic netlists, and analyzes the device inter-connection, then generates test patterns. Inter-device test can automatically find short (pin to pin, pin to power supply or ground), open and other issues.

Steps

Select menu Test – Inter-device Test. See screenshot below:

one Bo	🎇 Boundary Scan Test 📃 📼 📼					
<u>F</u> ile	<u>Test</u> Process Options <u>U</u> tilites Log <u>H</u> elp					
Ι	Scan JTAG Chain	^				
	Inter-device Test					
	Single Device Test					
	Manual Test					
		Ŧ				
•	۶. ۴					

You will see Inter-device Test Configuration dialog:

Inter-Device Test	t Configuration ×
Browse Netlist File	Capture/Allegro 🗸 🗸 with \$NETS Tag
Prefix Instruction Length	Prefix Data Length
Device A Browse BSDL File A	Index in Chain 0 Part Ref
Infix Instruction Length	Infix Data Length
Device B Browse BSDL File B	Index in Chain 1 Part Ref
Postfix Instruction Length	Postfix Data Length
Save OK Cancel	

About the Parameters

There are two DUTs. Let's call them DUT A / Device A and DUT B / Device B.

Set schematic netlist file, and choose the netlist file format.

Set **BSDL file**, **Part Ref** and **Index in JTAG Chain** for DUT A and B.

Prefix Instruction Length: Please input JTAG instruction length of all other devices ahead of DUT A. If there are more than one devices, please split them with "|" character. For example, '4 | 5' means there are two devices ahead of DUT in JTAG chain, and device at index 0 has a 4-bit JTAG instruction while device at index 1 has a 5-bit JTAG instruction. And you could find that the DUT is at index 2. Must left blank when no prefix device.

Infix Instruction Length: Please input JTAG instruction length of all other devices between DUT A and DUT B. Refer to Prefix Instruction Length. Must left blank when no infix device.

Postfix Instruction Length: Please input JTAG instruction length of all other devices behind of DUT B. Refer to Prefix Instruction Length. Must left blank when no postfix device.

Test Control File: This file is used to control other pins which are not inter-connected. Text file. Write one setting per line. Syntax: Part_Ref<TAB>Pin_Location<TAB>Output_Value.

An Example

Let's suppose a board with 6 devices in a single JTAG chain, and we are going to do inter-device test of U1 and U4.



The setting should be:

Int Int	er-Device Test Configuration	×
Browse Netlist File D:\Test\Sample.NE	T Capture/Allegro V With \$NETS Ta	ag
Prefix Instruction Length 6	Prefix Data Length 1	
Device A Browse BSDL File A D:\BSDL	\P1010.R1A.bsd Index in Chain 1 Part Ref U1	
Infix Instruction Length 10	Infix Data Length 1	
Device B Browse BSDL File B D:\BSDL	Vc4256vf256b.bsm Index in Chain 3 Part Ref U4	
Postfix Instruction Length 8 7	Postfix Data Length 1 1	
	Cancel	

Notes:

- All indexes are zero based.
- Except U1 and U4, other device are Bypass. The data length of the Bypass device is 1, so the data length is not required.

Tips

For you convenience, you could click **Save...** button to save the parameters to a text file with extension .ini. Next time just click the **Save...** button to load saved parameters.

Run the Test

Click **OK** after all parameters are set.

The software will do a JTAG chain scan and show result in log.

Then the software will parse BSDL files of devices in chain.

Then the software will check IDCODE.

After IDCODE checking passed, the software will parse netlist file.

The software will filter connection from all netlist according to Part Ref. You will see **Filtered Netlist** dialog.



It's a simple editor. You can edit the connections if you want.

That's because sometimes the pins are connected through a resistor or logic clue, but they will not be filtered automatically since they have same netlist name. But they are testable. You can add them manually.

Click **OK** to continue.

The software will analyze to find testable netlists.

You know, only netlist connected between DUT A and DUT B could be tested, and those connections that one device could output and the other device could input could be testable.

Testable Netlist	×
NET8: [(52 8)] [(246 8)] NET9: [(202 8)] [(122 8)] NET10: [(144 8)] [(138 8)] INTERCONNECT1: [(104 8)] [(214 8)] INTERCONNECT2: [(92 8)] [(76 8)]	
<	
ок	1.

Testable Netlist dialog will show testable netlists.

Click OK button.

The software will run test and show result.

BSTest	
(į)	24 item(s) tested, 96 test pattern(s) tested, all test patterns test PASS!
	OK

You could check detailed info in log.

The software will tell you failure items detected since V2.2.2.1.

The software will show pin location at the same time since V2.3.0.0.

An example screenshot:

BSTestd	
	24 item(s) tested, 96 test pattern(s) tested, 4 test pattern(s) test FAILED! Failure may be caused by below item(s): ====================================
	确定

UI Difference Under Different Launching Mode

Launching UI Display	Menu: Inter-Device Test	Menu: Batch Test	Automatically launched when startup
Display 'Edit Netlists' Dialog	Yes	No	No
Display 'Testable Netlists'	Yes	No	No
Confirmation Dialog			
Show Error Message	Yes	Yes	Yes
Show Success Message	Yes	Yes	No

Single Device Test

This automatic operation can detect short between pins (in fact, not only pins of JTAG device, but also pins of other devices connected to JTAG device), or short between I/O pins and power supply or ground.

Preparation

Before testing, please create a setting file by selecting menu Utilities –Edit Single Device Test Setting...:

010				Bo	unda	ry Scan Test	-	×	
<u>F</u> ile	<u>T</u> est	<u>P</u> rocess	<u>Options</u>	<u>U</u> tilities	<u>L</u> og	<u>H</u> elp			
				Edit	Single	e Device Test Setting			
				Extr	act Ne	etlists for Inter-Device Test			
							-		
								~	1
<								>	-
_					_		_		

A 'BSDL File' dialog will popup. Select correct BSDL and click OK:

		BSDL File	×
Browse BSDL File			
Save	ОК	Cancel	

Now the 'I/O Setting' dialog is shown:

I/O Setting						×	
<u>F</u> ile <u>U</u> tilities	;						
Port Name	Pin Location	Can Output	Can Input	Output Setting	Expected Input	Alias	^
PB00_00	2	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_01	3	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_02	5	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_03	4	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_04	6	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_05	8	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_06	7	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_07	9	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_08	11	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_09	12	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_10	13	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_11	14	true	true	z - Disabled 💌	z - Disabled 💌		
PB00_12	18	true	true	z - Disabled 💻	z - Disabled 💻		*

Output Setting

Output Setting	9
z - Disabled	~
z - Disabled	
x - Any	
1	
0	

Option	Output Status	Comments
z – N/A	This cell could not output.	
z – Disabled	This cell is outputable, but we	
	don't test it.	
x – Any	Output anything.	Pin under test should select this option.
1	Output '1' always.	The pin will stay on a certain status. It could be
		used to control some circuit.
0	Output '0' always.	The pin will stay on a certain status. It could be
		used to control some circuit.

Expected Input

Expected Input
z - Disabled 🗸
z - Disabled
Output
1
0

Option	Input Status	Comments
z – N/A	This cell could not input.	
Z – Disabled	This cell is inputable, but we	
	don't check it.	
Output	Changes with the Output.	Input should be the same as output. Pin under test
		should select this option.
		Attention: The output should not be z -
		N/A nor z - Disabled.
1	Input is '1'.	This pin should always input '1' normally, and
		other status when failure. It happens to the pin
		whose status is fixed.
0	Input is '0'.	This pin should always input '0' normally, and
		other status when failure. It happens to the pin
		whose status is fixed.

Save

Menu File – Save...:



Utilities

Alias

To improve the readability of test result, you could add alias to the pins. Select menu **Utilities** – **Get Alias from Netlist File...**:

C	I/O Setting							
	File	Utili	ties					
	Por		Get Alias from Netlist File					
	PBO		Aut	omatically Se	et to Maximiz	e Test	Disab	
	PB00_01 3 true true z -				z - Disak			

Auto Set to Max Testable

Select menu Utilities – Get Alias from Netlist File...:

Utilities					
	Get Alias from Netlist File				
	Automatically Set to Maximize Test				
	Batch Set with Port Name Reg Exp				

Attention: This utility automatically generate an general and maximized-possible-testable setting, but it should be revised based on your board design since the pin connections vary on each board.

Batch Set with Port Name Regular Expression

Select menu Utilities -Batch Set with Port Name Regular Expression...:



Then input a regular expression:

Port Name	Pin Location	Can Output	Can Input	Output Setting	Expected Input	Alias
EIM_CS1	J23	true	true	z - Disabled 💻	z - Disabled 💻	
EIM_D16	C25	true	true	z - Disabled 💌	z - Disabled 💻	
EIM_D17	F21	truc	+====	- Disablad	- Qisabled 🛨	
EIM_D18	D24 Pin Na	me Regular E	xpression		📕)isabled 👤	
EIM_D19	G21 Enter	a regular ex	(pression))isabled 💻	
EIM_D20	G20	D[O-9]*	_		isabled 💻	
EIM_D21	H20			OK Cancel)isabled 💻	
EIM_D22	E23	true	true	z - Disabled 💻	z - Disabled 💌	
EIM_D23	D25	true	true	z - Disabled 💌	z - Disabled 💻	
EIM_D24	F22	true	true	z - Disabled 💌	z - Disabled 💻	
EIM_D25	G22	true	true	z - Disabled 💌	z - Disabled 💻	
EIM_D26	E24	true	true	z - Disabled 💌	z - Disabled 💻	-

The setting dialog appears after 'OK' button is clicked:

Please select output and input settings for these ports/pins. In this case, we hope output both 1 and 0, and input should be same as input. (Please refer to <u>Output Setting</u> and <u>Expected Input</u> for more info.) So:

Port Setting							
Output	×-Any •						
Input	Output 🗸						
	[2					
	OK Cancel)					

Click OK, ports/pins met the regular expression will all be set:

File Utilities Port Name Pin Location Can Output Can Input Output Setting Expected Input Alias EIM_CS1 J23 true true z - Disabled z - Disabled z EIM_D16 C25 true true x - Any Output Image: Control output Ima	I/O Setting									
Port Name Pin Location Can Output Can Input Output Setting Expected Input Alias EIM_CS1 J23 true true z - Disabled v z - Disabled v a EIM_D16 C25 true true x - Any v Output v a EIM_D17 F21 true true x - Any v Output v a EIM_D18 D24 true true x - Any v Output v a EIM_D19 G21 true true x - Any v Output v a EIM_D20 G20 true true x - Any v Output v a EIM_D21 H20 true true x - Any v Output v a EIM_D22 E23 true true x - Any v Output v a EIM_D23 D25 true true x - Any v Output v a EIM_D25 G22 true true x - Any v Output v a EIM_D26 E24 true true x - Any v Output v <td< td=""><td>File Utilities</td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td></td<>	File Utilities									
EIM_CS1 J23 true true z - Disabled v z - Disabled v EIM_D16 C25 true true x - Any v Output v EIM_D17 F21 true true x - Any v Output v EIM_D18 D24 true true x - Any v Output v EIM_D19 G21 true true x - Any v Output v EIM_D20 G20 true true x - Any v Output v EIM_D21 H20 true true x - Any v Output v EIM_D21 H20 true true x - Any v Output v EIM_D22 E23 true true x - Any v Output v EIM_D23 D25 true true x - Any v Output v EIM_D25 G22 true true x - Any v Output v EIM_D26 F24 true	Port Name	Pin Location	Can Output	Can Input	Output Settir	ng	Expected Inp	ut	Alias	^
EIM_D16 C25 true true x - Any Output Image: Constraint of the state of the stat	EIM_CS1	J23	true	true	z - Disabled	•	z - Disabled -	•		
EIM_D17 F21 true true x - Any Output Image: Constraint of the state of the stat	EIM_D16	C25	true	true	x - Any	•	Output -	•		
EIM_D18 D24 true true x - Any Output Image: Constraint of the state of the stat	EIM_D17	F21	true	true	x - Any	•	Output -	•		
EIM_D19 G21 true true x - Any Output Image: Constraint of the state of the stat	EIM_D18	D24	true	true	x - Any	•	Output -	•		
EIM_D20 G20 true true x - Any Output Image: Constraint of the second s	EIM_D19	G21	true	true	x - Any	•	Output -	•		
EIM_D21 H20 true true x - Any Output EIM_D22 E23 true twe x - Any Output Image: Comparison of the comparis	EIM_D20	G20	true	true	x - Any	•	Output -	•		
EIM_D22 E23 true twe x - Any Output EIM_D23 D25 true true x - Any Output Image: Comparison of the comparis	EIM_D21	H20	true	true	x - Any	•	Output -	•		
EIM_D23 D25 true true x - Any Output Image: Constraint of the state of the stat	EIM_D22	E23	true	t¦⊋e	x - Any	-	Output -	-		
EIM_D24 F22 true true x - Any Output Image: Constraint of the state of the stat	EIM_D23	D25	true	true	x - Any	•	Output -	•		
EIM_D25 G22 true true x - Any Output FIM_D26 F24 true true x - Any Output	EIM_D24	F22	true	true	x - Any	•	Output -	•		
FIM D26 F24 true true x - Any V Output V	EIM_D25	G22	true	true	x - Any	•	Output -	•		
	EIM_D26	E24	true	true	x - Any	•	Output -	•		Ŧ

Edit Saved Setting File

Menu File – Open...

File	Utilities	5					
	Open			Ca			
	Save						
	Exit		\vdash	tru			
			1				
PB00_02		5		tru			

Steps

Select menu Test – Single Device Test:



You will see Single Device Test Configuration dialog:

Single Device Test Configuration							
Browse Setting File							
Prefix Instruction Length		Prefix Data Leng	jth				
Browse BSDL File		Ind	ex in Chain	D			
Postfix Instruction Length		Postfix Data Ler	ngth				
ок(Cancel						
				111			

Browse Setting File: Select the saved setting file in above section.

Prefix Instruction Length: Please input JTAG instruction length of all other devices ahead of DUT. If there are more than one devices, please split them with "|" character. For example, '4 | 5' means there are two devices ahead of DUT in JTAG chain, and device at index 0 has a 4-bit JTAG instruction while device at index 1 has a 5-bit JTAG instruction. And you could find that the DUT is at index 2. Must left blank when no prefix device.

Post Instruction Length: Please input JTAG instruction length of all other devices behind of DUT. Refer to Prefix Instruction Length. Must left blank when no postfix device.

When Setting File, BSDL file of DUT and Index of DUT are set, click OK button.

The software will run rest according to Setting File and show testing result.

Example 1

The **Setting File** contains 8 items to be tested. They are D0 to D7.

Test on Good Board

No error found.



The log will show detailed info of test.

Single Device Test is n	unning					
Output 0 Input R	tesult Port					
0111111101111111	G6 / D0					
10111111 10111111	H9/D1					
11011111 11011111	H7/D2					
11101111 11101111	H4/D3					
11110111 11110111	G3 / D4					
11111011 11111011	H6 / D5					
11111101 11111101	H1/D6					
11111110 11111110	12 / D7					
Output 1 Input R	tesult Port					
10000000 10000000	G6 / D0					
01000000 01000000	H9/D1					
00100000 00100000	H7/D2					
00010000 00010000	H4/D3					
00001000 00001000	G3 / D4					
00000100 00000100	H6 / D5					
00000010 00000010	H1/D6					
00000001 00000001	I2/D7					
8 item(s) tested, 16 test pattern(s) tested, all test patterns test PASS!						

Short-Circuit Issue

We manually connect pin D0 and D1 with a wire. This time we'll be told failure found in test.

BSTest	\mathbf{X}
1	8 item(s) tested, 16 test pattern(s) tested, 4 test pattern(s) test FAILED!
	ОК

The software will tell you failure items detected since V2.2.2.1. Furthermore, the software

will show pin location of failed item since V2.3.0.0. Display format: **Port Name @ Pin Location** / **Alias**. Please note pin location or alias will not be displayed is it's empty. See screenshot below:

BSTestd	
4	8 item(s) tested, 16 test pattern(s) tested, 4 test pattern(s) test FAILED! Failure may be caused by below item(s): ====================================
	确定

Log showed:

Single Device Test is running
Output 0 Input Result Port
01111111 1111111 ? G6 / D0
10111111 1111111 ? H9 / D1
11011111 11011111 H7 / D2
11101111 11101111 H4/D3
11110111 11110111 G3/D4
11111011 11111011 H6/D5
11111101 11111101 H1/D6
11111110 11111110 I2/D7
Output 1 Input Result Port
10000000 11000000 ? G6 / D0
01000000 11000000 ? H9 / D1
00100000 00100000 H7 / D2
00010000 00010000 H4/D3
00001000 00001000 G3/D4
00000100 00000100 H6/D5
00000010 00000010 H1/D6
00000001 00000001 I2 / D7
8 item(s) tested, 16 test pattern(s) tested, 4 test pattern(s) test FAILED!

It's easy to find D0 and D1 didn't pass the test since we shorted them.

More...

In fact, not only short circuit between pins of JTAG device, but also short circuit between pins of other devices connected to JTAG device could be found.

Example 2

The **Setting File** contains 64 items to be tested. They are d(0) to d(63).

Test on Good Board



No error found.

Short Circuit with Power

We manually connect pin d(47) and 3.3V with a wire.



Detailed log:



We could see easily that pin d (47) doesn't pass the test.

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Short Circuit with GND

We manually connect pin d(45) and GND with a wire



000000001000000000000000000000000000000	d
000000001000000000000000000000000000000	dı
000000000100000000000000000000000000000	dı
	d
000000000001000000000000000000000000000	d
000000000000000000000000000000000000000	d
	d
	d
<u>, 000000000000000000000000000000000000</u>	d I
	? di
	d
	d
	d
	d
	d
	d
	d
	d
	d
	d

Obviously, d(45) could not pass the test.

Short-Circuit Between Pins

We manually connect pin d(45) and d(46) with a wire.:



Detailed log of test when outputting 0:



We could see that there are always two pins test failed no matter what value is outputting (0 or 1). The two pins are d(45) and d(46).

More...

Examples above just list part of pins. You can add as more as you want in the test setting file.

Peripheral Test

Edit JFP Configuration File

Follow "JFP Edit Cfg File User Manual(ENU).pdf" to get a JFP configuration file.

Run

Select menu Test – Peripheral Test.... See screenshot below:

010 000	Bound	ary Scan Test _SIMU _OFFLINE			×
File	Test	Process Options Utilities Log H	elp		
Tryir		Scan JTAG Chain STest.ini	l		~
No A		Inter-device Test			
		Single Device Test			
		Peripheral Test			
		Batch Test			
		Manual Test			
	_				
					\sim
_ <					>

Select configuration file. See screenshot below:

Browse JFP Cfg File X				
\leftrightarrow \rightarrow \checkmark \uparrow	<pre> « setting_cfg > JFP > </pre>	Search JFP	م	
Organize 🔻	New folder		==	
^	Name	Date modified	Туре ^	
	FSL_MPC8349E-MITX_BSTJFP(CS0).ini	2013/8/14 3:23 PM	Configuration sett	
	FSL_MPC8548PC_BSTJFP.ini	2013/8/22 1:02 PM	Configuration sett	
	FSL_MPC8560ADS_BSTJFP.ini	2015/7/13 10:52 PM	Configuration sett	
	FSL_MPC8569E-MDS_BSTJFP(NOR@CS0)	2015/7/17 4:48 PM	Configuration sett	
	FSL_P1010-RDB_BSTJFP(NOR@CS0).ini	2013/12/10 6:07 PM	Configuration sett	
	FSL_P1021RDB_BSTJFP(NOR@CS0).ini	2013/12/24 5:28 PM	Configuration sett	
	FSL_P2020RDB_BSTJFP(NOR@CS0).ini	2013/8/3 8:28 PM	Configuration sett	
	FSL_P2041RDB_BSTJFP(NAND@CS1).ini	2016/3/30 1:52 PM	Configuration sett 🗸	
× •	c		>	
	File name: FSL_MPC8548PC_BSTJFP.ini	✓ JFP Configu	ration Files (*BSTJFF $ \sim $	
		<u>O</u> pen	Cancel	

The software will show the run result.

Batch Test

Edit Workspace File

Follow "FileHelper User Manual(ENU).pdf" to create or edit a workspace file.

Run

Select menu Test – Batch Test.... See screenshot below:

×
^
\sim
>

Select workspace file. See screenshot below:

Browse Workspace File				×
\leftarrow \rightarrow \checkmark \uparrow \bigcirc « Self \rightarrow def	emo > setting_cfg > BST	~ Ū	Search BST	ρ
Organize 🔻 New folder			:== ▼	•
setting_cfg ^	Name		Date modified	Туре
📙 BST	Common		2016/5/16 8:12 AM	File folder
Common	BSTest.ini		2016/5/19 9:34 AM	Configuratio
EthCfg				
JFP				
doc				
flash_para				
📙 media				
proprietary				
Setup				
🔶 Favorites				
InstallAnywhere				
T tala	<			>
File <u>n</u> ame: E	3STest.ini	~	Legacy BSTest Workspace	e Files 🗸
L			<u>O</u> pen (Cancel

The software will show the run result.

PLD Configuration

Currently .svf and .vme files are supported. *Note:*

- A PLD maybe a CPLD/EPLD, and could also be a FPGA.
- .*svf file could be used to perform a test besides configuration.*

We show example of .svf in this manual. To .vme file, it's very similar.

Get .svf File

Almost every EAD software could convert programming file from other format to .svf format. Ask help from your PLD vendor if you have difficulty.

Start

Select menu **Process** - **.svf File**. See screenshot below:

🏦 Bo	undaŋ	y Scan Test					x
<u>F</u> ile	<u>T</u> est	Process Options	<u>U</u> tilites	<u>L</u> og	<u>H</u> elp		
1		svf					*
		vme					
_							-
H_*							л.

Set .svf File

When SVF File Processor dialog pops, click Browse... button.

SVF File Processor		2	3
Browse		<u>A</u> dd	
		<u>elete</u>	•
Run Exit Debug Error: 16	_		
Log Empty			
			*
			Ŧ
		•	

Click Add button after file is selected.

SVF File Processor	
Browse e:\test.svf	Add
	Delete
Run Exit Debug Error: 16	
Log Empty	
	^
- 4	

Screenshot after file added:

SVF File Processor	
Browse e:\test.svf	Add
e:\test.svf	Delete
Run Exit Debug Error: 16	
	^
	▼

You may add multi files. The software will process them one by one.

If you want to remove one svf file, just select it and click **Delete** button. See screenshot below:

SVF File Processor	
Browse e:\test2.svf	Add
e:\test.svf e:\test2.svf	Delete
Run Exit Debug Error: 16	
Log Empty	
	*
	
	P

Run

Click **Run** button when setting is done. The software will show the run result.

PseudoCLI Feature

Fully automatic operation without any mouse clicking could be implemented with additional PseudoCLI feature. This feature will automatically close GUI and provide return code to caller. Return code:

- -1: License error;
- 0: OK;
- n>0: The *n*th operation failed.

Please note: The GUI will pop up a message box when error occurs. Turn off this by setting [Option] ExitWhenFail=true in the workspace file. The caller must check the return value.

Date	Version	Author	Changes
2020/4/19			Add PseudoCLI feature;
2019/8/18			Add output constraint to Expected Input for Single Device Test;
2019/1/31			Add Batch Set with Port Name Regular Expression
2016/8/12			Add Section "Batch Test";
2016/8/2			Add IDT Test Control File syntax;
2016/7/20			• Add Section "Peripheral Test";
			• Re-organize sections, current order: Manual Test,
			Inter-device Test, Single Device Test, Peripheral Test, PLD
			Configuration;
2016/5/27			• Add: Attention: To get better test result and
			wider test coverage, please keep FPGA, CPLDs
			blank when testing, and do not program or
			configure them before test. And please keep
			CPUs in idle status, i.e. do not program their
			Boot ROMs or Flashs before test.
			• The output cell of IO Setting table for Manual Test becomes
			Edit box instead of Combobox since V2.4.0.2, so add 'type
			the output pattern string in Edit box of the cell';
2014/12/2			• Move V2.2.2.1 improvement to first failure case;
			• Add V2.3.0.0 feature;
2014/11/20			• Add section <u>UI Difference Under Different Launching</u>
			Mode;
2014/11/14			• Add screenshot of V2.2.2.1 which will show detected failure
			pins besides failure counter;
2014/11/13			• Add <u>Preparation</u> section in <u>Single Device Test</u> ;
			• Add <u>An Example</u> in <u>Inter-Device Test</u> ;
			• Add <u>Tips</u> in <u>About the Parameters</u> section in <u>Inter-Device</u>
			<u>Test;</u>
			• Update text and screenshot because more netlist file formats
			are supported;
2014/6/9			• Add line above footer;
2013/7/30			• Format optimization;
2013/7/28			• First Release

Revision History